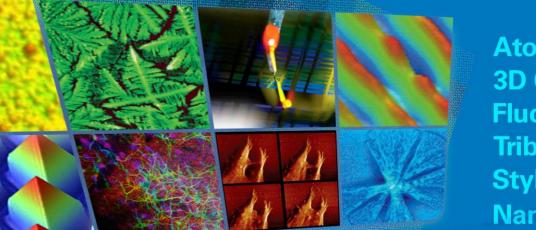
Recent Advancements in Nanoscale IR Spectroscopy and Imaging

Anirban Roy, Qichi Hu, Honghua Yang, Miriam Unger and Curtis Marcott





Atomic Force Microscopy 3D Optical Microscopy Fluorescence Microscopy Tribology Stylus Profilometry Nanoindentation

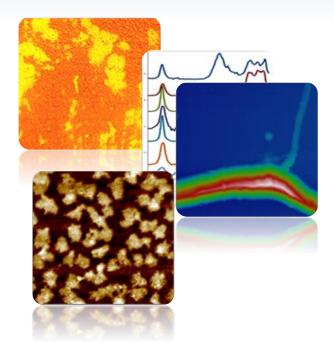
Innovation with Integrity

Bruker Nano Surfaces Division

Outline

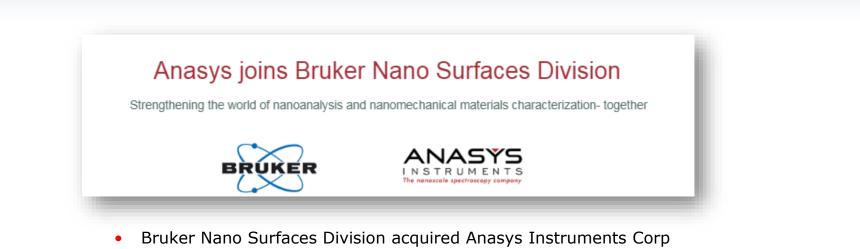


- Company Background
- Introduction to AFM-IR
- Latest AFM-IR Advancements
 - Resonance Enhanced AFM-IR
 - HyperSpectral Imaging/Spectroscopy
 - Tapping AFM-IR Imaging/Spectroscopy
 - Technical Overview
 - Applications
- s-SNOM Technology and Applications
- Tunable IR Laser Options
- Summary



Bruker Nano Acquires Anasys Instruments





- on April 10th 2018
- All nanoIR products are now integrated into the Bruker Nano Product Support



Nanoscale IR spectroscopy



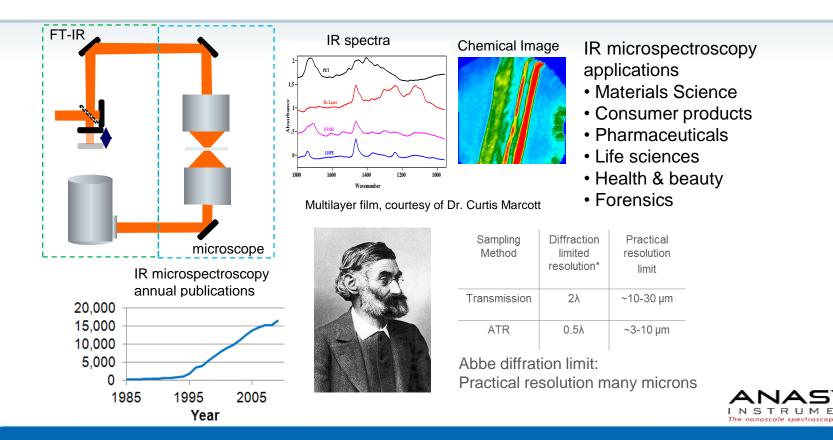


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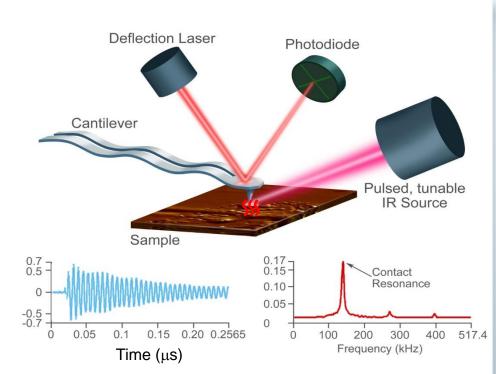


Power and Limitations of Infrared Microspectroscopy



AFM-Based IR Spectroscopy (AFM-IR)





Dazzi, A.; Prazeres, R.; Glotin, F.; Ortega, J.M.; Opt. Lett. 2005, 30, 2388-2390.



Alexandre Dazzi 2014 Ernst Abbe Award

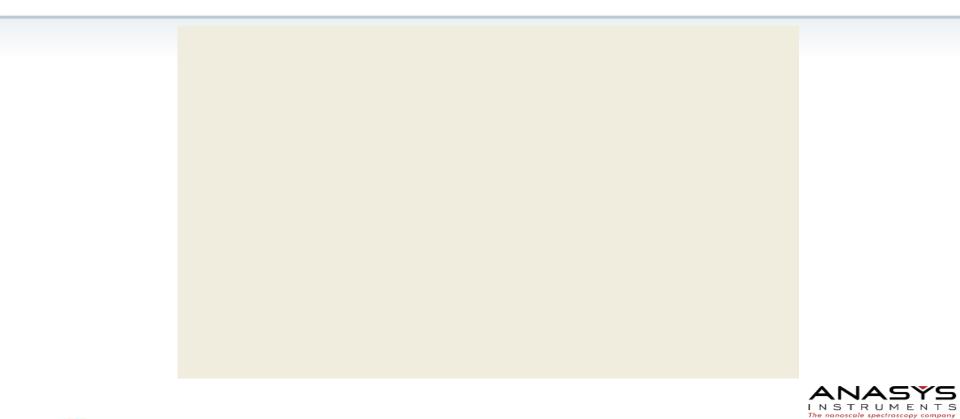


Ernst Abbe



Nanoscale IR Spectroscopy

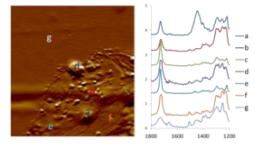




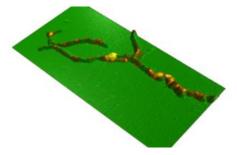


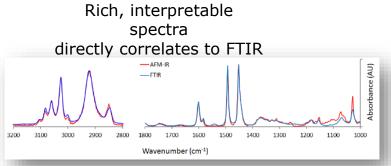
nanoscale infrared imaging & spectroscopy capabilities

Nanoscale IR chemical analysis

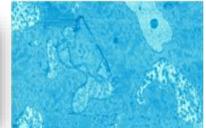


Chemical composition & nanoscale property mapping





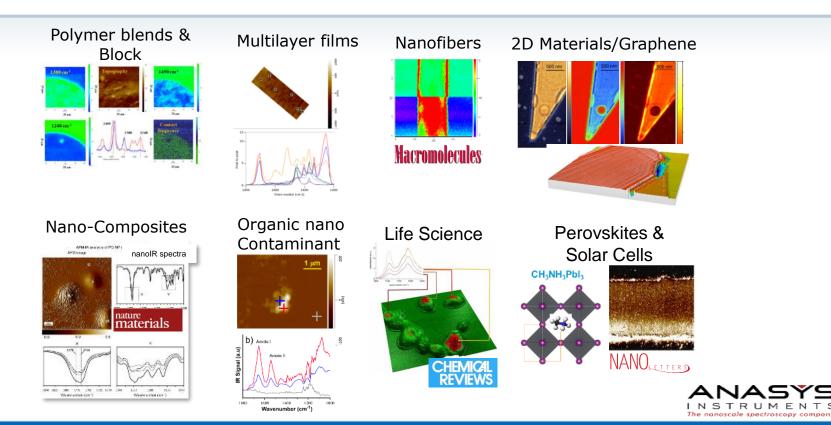
Monolayer sensitivity & high spatial resolution





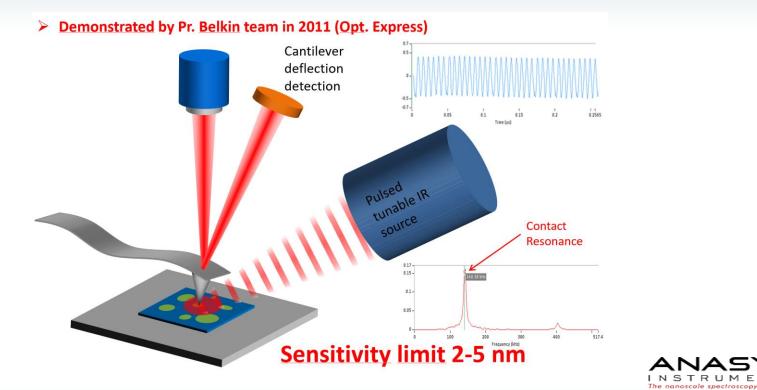
Broad range of nanoIR applications





Resonance Enhanced Mode



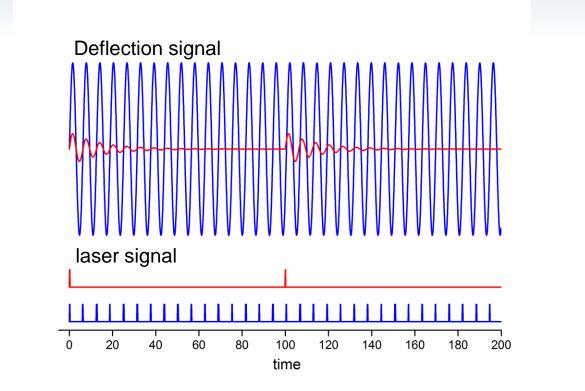






S R Resonance Enhanced Mode

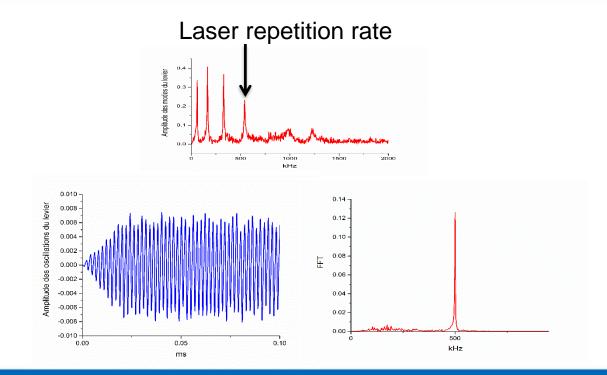






Forced resonance makes AFM-IR more sensitive

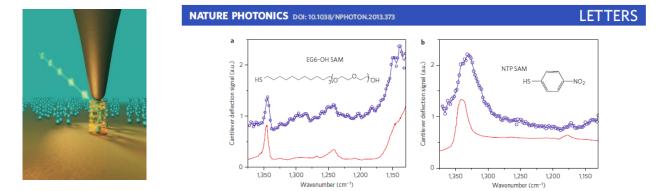






Single Monolayer Sensitivity





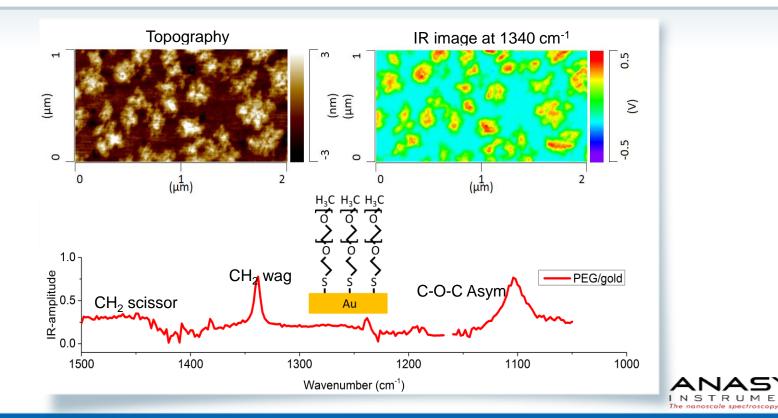
F. Lu, M. Jin, and M.A. Belkin, *Nat. Photonics* **8**, 307–312 (2013).



Resonance enhanced AFM-IR of PEG monolayer

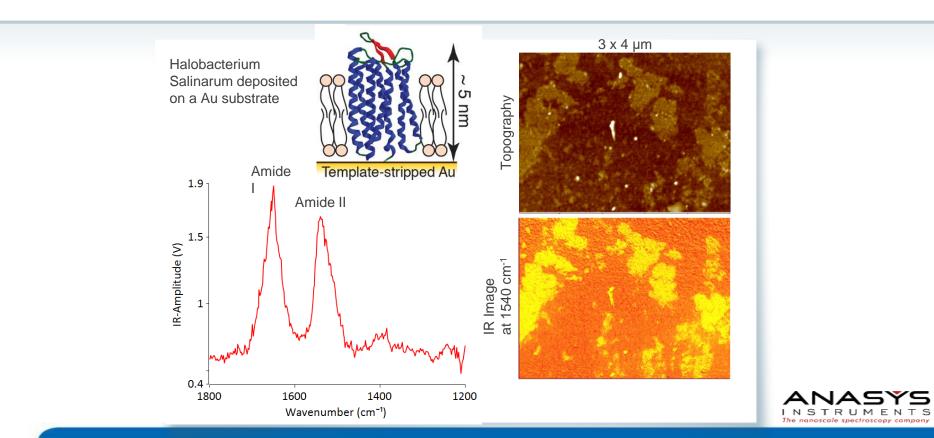


S R



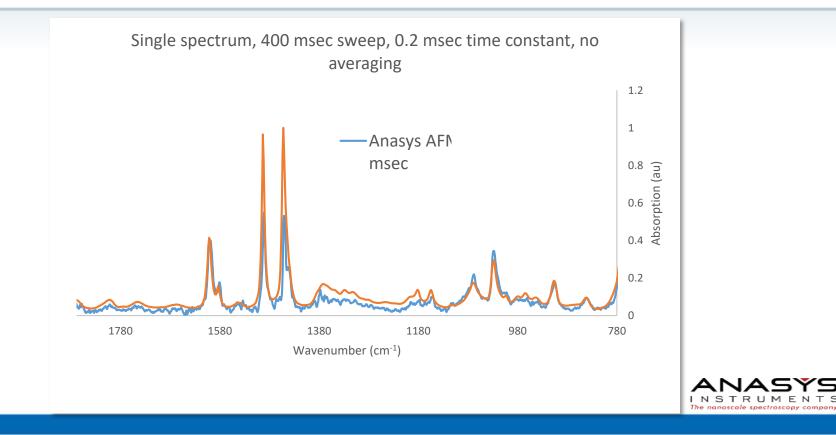
Purple Membrane (Resonance Enhanced AFM-IR)





QCLs are getting faster!





Faster Scanning Enables Hyperspectral Imaging



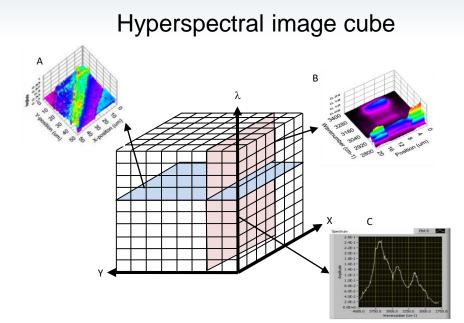


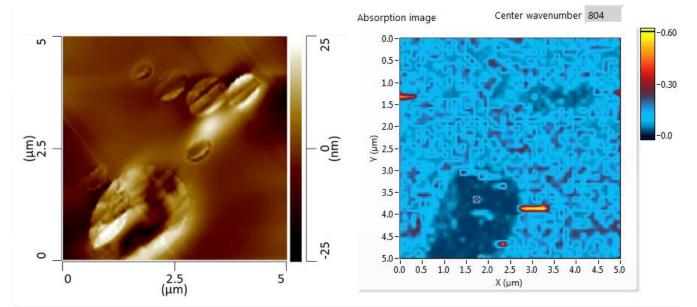
Figure 5. Illustration of the hyperspectral image cube. High speed AFM-based IR spectroscopy allow for the first time practical hyperspectral imaging, i.e., where spectra are mapped at matrix of XY points. One can extract segments of the hyperspectral cube to obtain (A) chemical maps that show spatial variation in absorption at a given wavelength, (B) spectral line maps showing the variation in spectra in one direction, or (C) individual spectra at any X,Y location.



Hyperspectral animation



 $5-\mu m \times 5-\mu m$, 50 x 50 spectrum array on PS/PMMA/epoxy blend



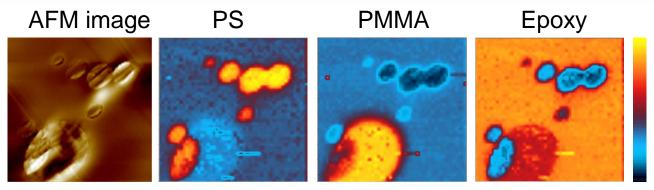
Move cursor onto above image and click on arrow to start animation



Hyperspectral array PCA weight maps



 $5\text{-}\mu\text{m}$ x $5\text{-}\mu\text{m}$, 50 x 50 spectrum array on PS/PMMA/epoxy blend



- New hyperspectral imaging provides point by point spectra over a large number of data points to provide an array of spectra and chemical images at specific wavenumbers
- Principle component analysis can be applied to identify specific chemical components and their spatial distribution



NEW nanoIR3 platform configurations

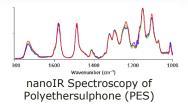


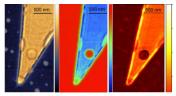
nanoIR3[™] - Latest Generation nanoIR platform with Tapping AFM-IR

- · Highest performance nanoIR spectra with AFM-IR
- Sub-10nm resolution IR chemical imaging with Tapping AFM-IR
- Correlates to FTIR & industry databases
- Easy to use for fast, productive measurements

nanoIR3-s[™] High Performance IR nano-spectroscopy

- Complementary s-SNOM & Tapping AFM-IR
- Highest Performance IR nano-spectroscopy
- Broadband Spectroscopy & Chemical Imaging
- Nanoscale property mapping
- Versatility & Easy to Use





Plasmonic Imaging on Graphene with Tapping AFM-IR & s-SNOM

nanoIR3-s[™] S-SNOM - High Performance s-SNOM Imaging

- IR s-SNOM platform for optical & chemical Imaging
- Supports multiple laser types, visible, nearIR
- Electrical nanoscale property mapping
- Upgradeable to nanoIR-spectroscopy

s-SNOM imaging Phase and Amplitude on HbN





Sample Environmental Control



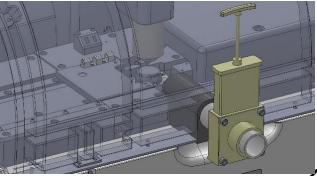
Humidity control & heater & cooler

- For control of humidity/gas & temperature for in-situ AFM-IR
- 4% to 95% non condensing
- 4°C to 80°C heating and cooling

C .	Availa humi control	dity	Maximum gas flow	Maximum X-Y motorized movement
	4 – 9 non-cond	5%, densing	250 ml/min	2mm x 2mm
Available temperature range		Available temperature range when paired with an environmental enclosure		
4 – 80 °C*		-20 – 80 °C		
*Evaporation and condensation on the sample may impact results.				

Sample transfer port for nanoIR3-s

- Protects sample in controlled gas environment from glove box to nanoIR system to protect
- includes integrated humidity sensor with optional high sensitivity humidity and oxygen sensors





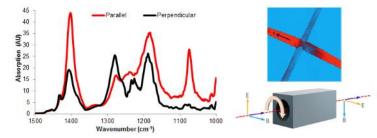
IR Polarization Control & extended IR range



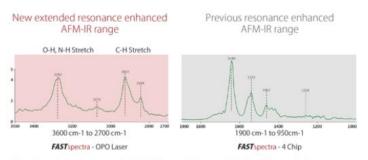
Polarization control

Allows users to study molecular orientation with nanoscale spatial resolution by changing the input polarization of the IR light while studying the associated changes in the nanoscale IR spectra and/or chemical maps at a certain wavenumber.

Polarizer Option Optional & upgradeable



(L) AFM-IR spectra on electrospun PVDF fibers under two different IR polarizations (R) IR absorption image at 1404 cm⁻¹ of crossed PVDF fibers under polarized illumination. (polarization direction shown by arrow)



FASTspectra[™] OPO mid-IR laser

The new high pulse rate OPO laser extends the wavelength range of Resonance Enhanced AFM-IR to cover the 2700 to 3600cm⁻¹ wavenumbers, extending capability to important spectroscopic regions and addressing wider range of applications, while still providing direct correlation to FTIR at the nanoscale.

Nylon 12 nanolR spectrum measured with both the new FASTspectra OPO and FASTspectra QCL lasers. Important C-H stretch, N-H stretch and OH regions are now enabled with rich interpretable data

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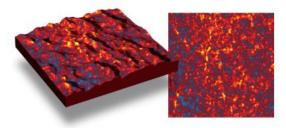
nanoIR nanoscale property mapping modes



Conducting AFM (CAFM):

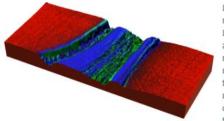
(Application Module)

Allows the user to obtain simultaneous height and current flow maps of the sample surface. Available on all Anasys systems.



Height (Left) and Conductivity (Right) images of a nanocomposite polymer.

Lorentz Contact Resonance mode

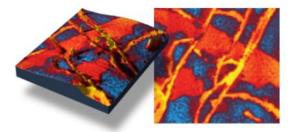


LCR composite image made by overlying the LCR amplitudes collected at three different contact resonances. These resonances were selected to highlight the varying ratios of the lignin and cellulose which compose the sample.

Kelvin Probe Force Microscopy (KPFM)

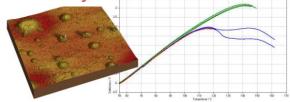
(Application Module)

Allows the user to obtain surface potential measurements. Available on all Anasys systems.



Height (Left) and Surface Potential (Right) images of a nanocomposite polymer.

Nano thermal analysis



Nanoscale thermal analysis of a PS-PMMA blend deposited on glass. A scan (left) shows indents in the surface caused by temperature ramps (right). The data from the PS (red) and PMMA (green) clearly differentiate the two materials. Also shown is data from a thin film of PS on PMMA (blue) showing the initial penetration of the PS followed by the melting of the PMMA.



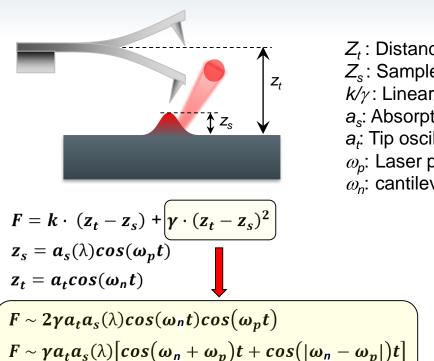
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23

Tapping AFM-IR: Technical Overview Concept



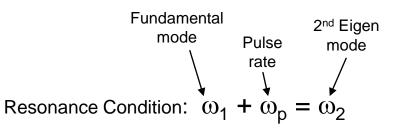


Sum frequency

 Z_t : Distance of the Tip Z_s : Sample expansion (photothermal)

- k/γ : Linear/non-linear force constant
- $a_{\rm s}$: Absorption coefficient
- a_{t} : Tip oscillation amplitude
- $\omega_{\rm p}$: Laser pulse rate

 ω_n : cantilever eigen mode frequency (n=1,2,3...)

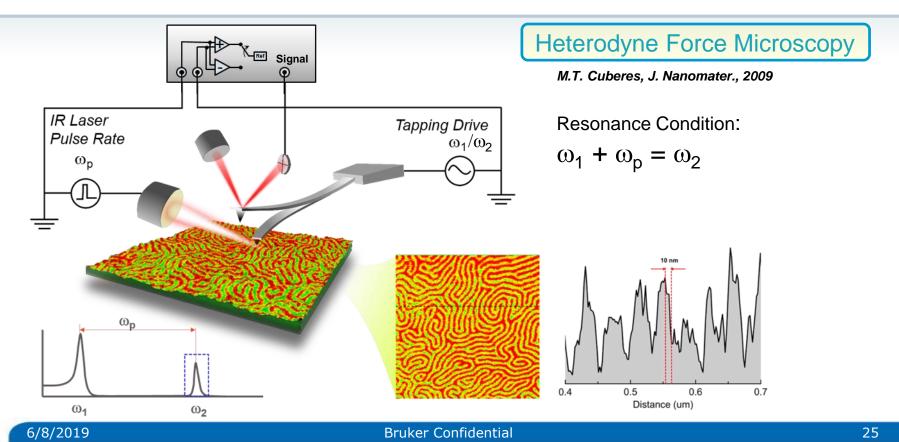


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Diff. frequency

Tapping AFM-IR: Technical Overview Schematic





Tapping AFM-IR: Key features

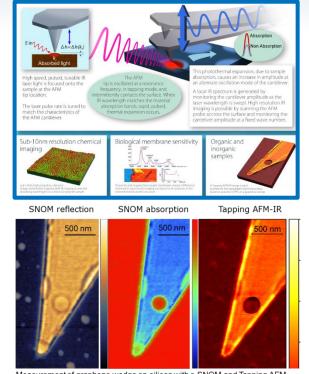


Broad Application range:

- Hard/soft sample, Adhesives, Membranes, Particulates
- Minimal sample/tip degradation due to absence of lateral forces

Improved Sensitivity:

- Sensitivity enhanced by cantilever Q-factor new probes
- AFM detector with higher sensitivity
- Efficient optical beam delivery optics with minimal loss
- High Spatial Resolution:
 - Spatial resolution extends to ~10 nm or better
- Multimodal Imaging:
 - Simultaneous chemical and viscoelastic property (Tapping Phase) imaging



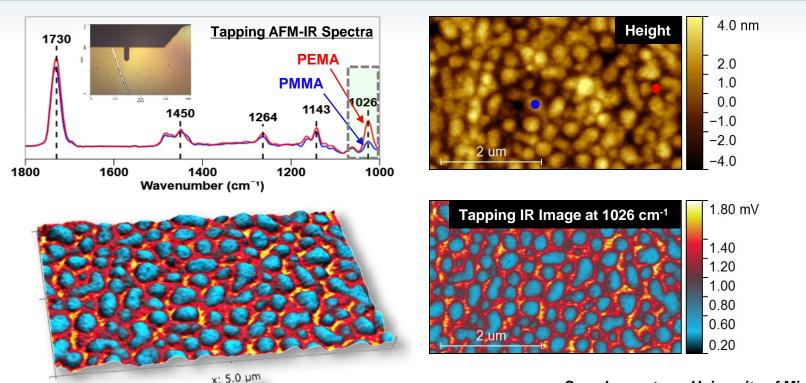
Measurement of graphene wedge on silicon with s-SNOM and Tapping AFM-IR show plasmonic effects at the edge

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Tapping AFM-IR: Applications Polymer 01: PEMA/PMMA Blend



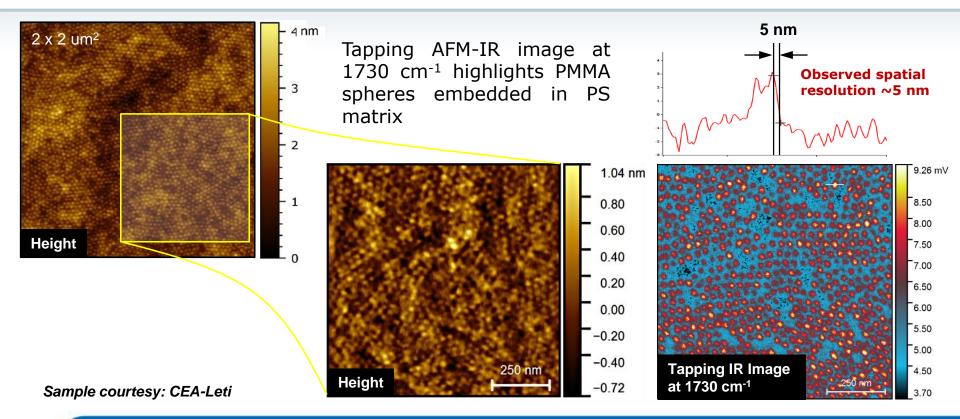


Sample courtesy: University of Minnesota



Tapping AFM-IR: Applications Polymer 02: PS/PMMA block copolymer



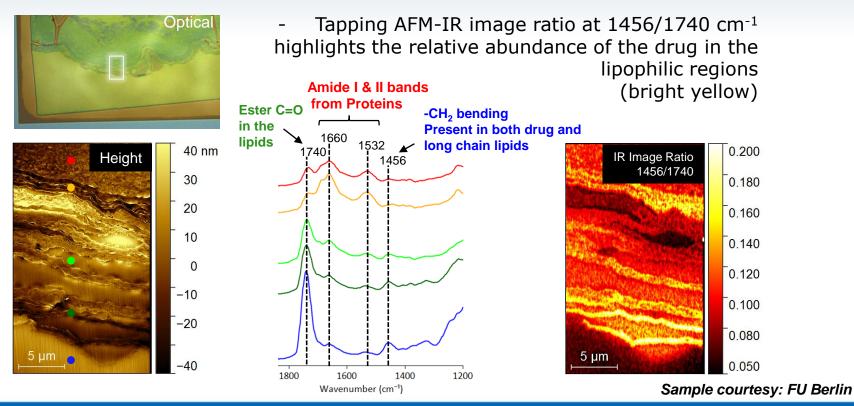


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Tapping AFM-IR: Applications Bio-pharmaceuticals 01: Skin/Dexamethasone



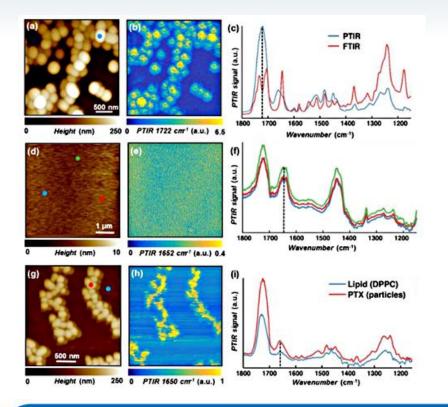


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Tapping AFM-IR: Applications Bio-pharmaceuticals 02: Anti-cancer drug delivery





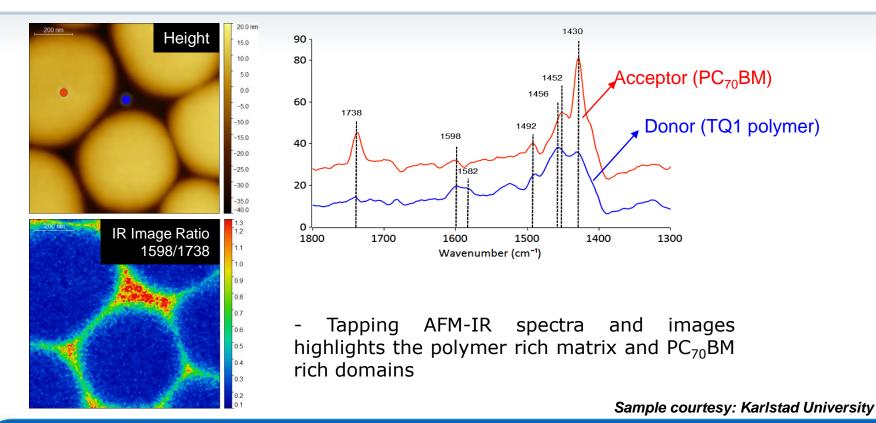
- Paclitaxel, a power anti-cancer drug, suffers from low efficacy and side effects due to low water solubility/recrystallization
- Recent study by Centrone and coworkers highlights the use of Tapping AFM-IR technology to explore the effect of different encapsulations in drug delivery
- High resolution compositional sensitivity of this technique unfolds new developments of lipid-polymer hybrid films in drug delivery applications

Centrone et al., Analyst, 2018, 143, 3808-3813

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Tapping AFM-IR: Applications Organic Photovoltaics: TQ1/PC₇₀BM Blend



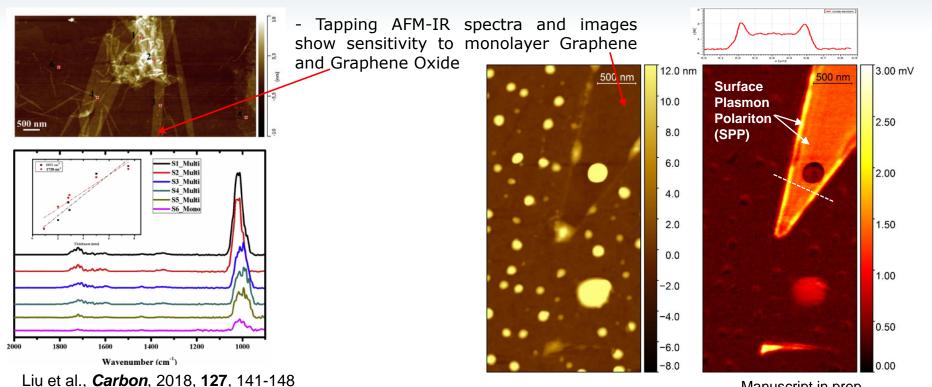


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Tapping AFM-IR: Applications 2D Materials: Graphene/Graphene Oxide





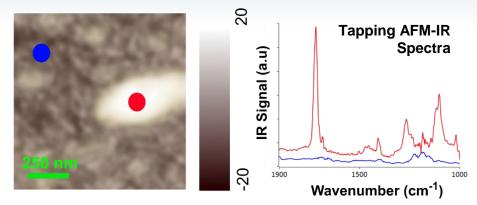
Manuscript in prep

6/8/2019

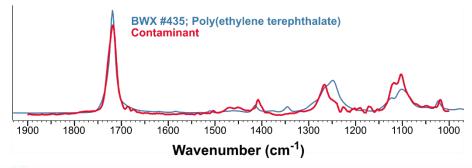
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Tapping AFM-IR: Applications Failure Analysis: Organic Nanocontaminations





FTIR Library Search



"...Knowing why devices fail is a must when designing next-generation products.."

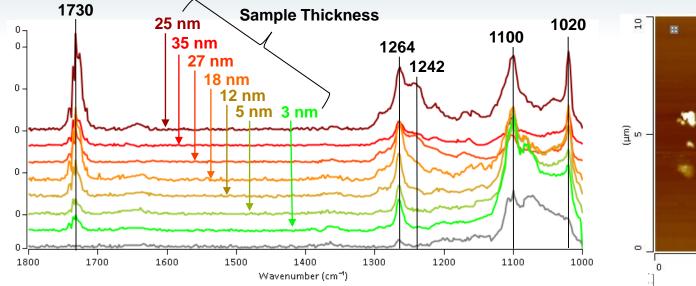
> V. Lakshminarayanan www.rfdesign.com, 2011

- AFM-IR technology complements traditional analytical tools used for failure analysis in nanoscale semiconductor devices/architectures
- Enhanced sensitivity extends to samples with thickness <20 nm
- Tapping AFM-IR technology demonstrates positive identification of nanoscale organic contaminants on Silicon wafer

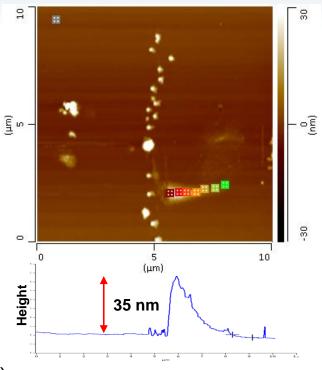
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Tapping AFM-IR Measurements on nanocontaminant sample

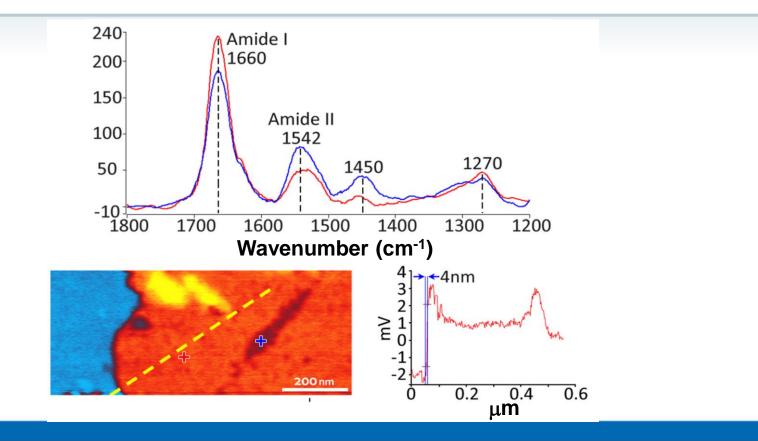




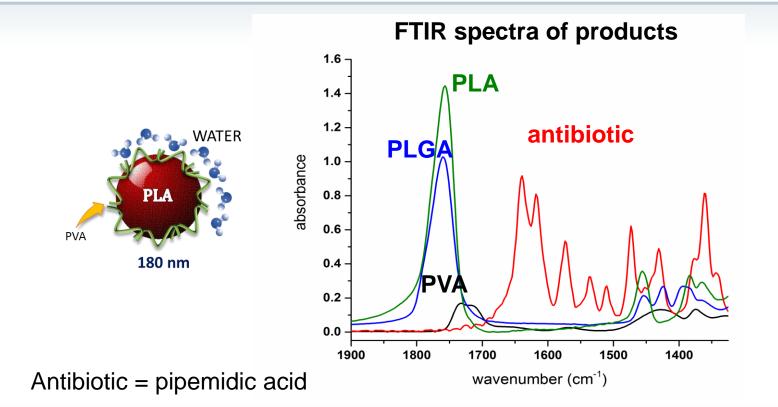
- Each spectrum is an average of 5 measurements, **NOT** smoothed
- Tapping AFM-IR spectra show absorption bands consistent with earlier measurements performed onsite – contamination is most likely synthetic polyester (PET/PBT)
- IR signal sensitivity goes down to 3 nm thick residue (bright green)







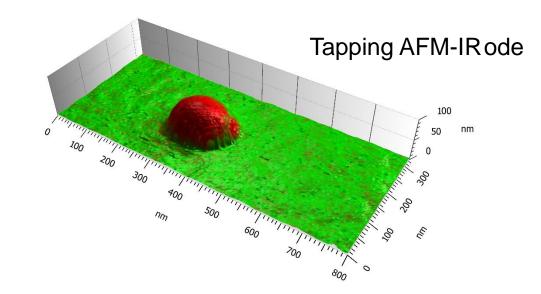






PLA/PVA nanoparticle

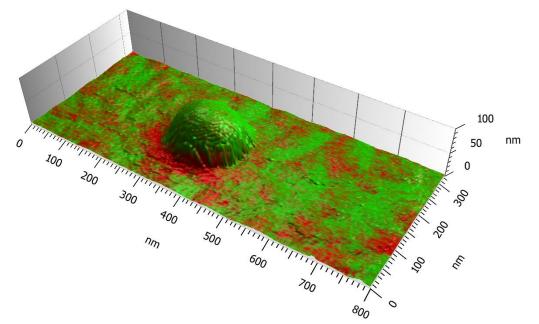
Mapping at 1760 cm⁻¹ center on ester carbonyl band of PLA





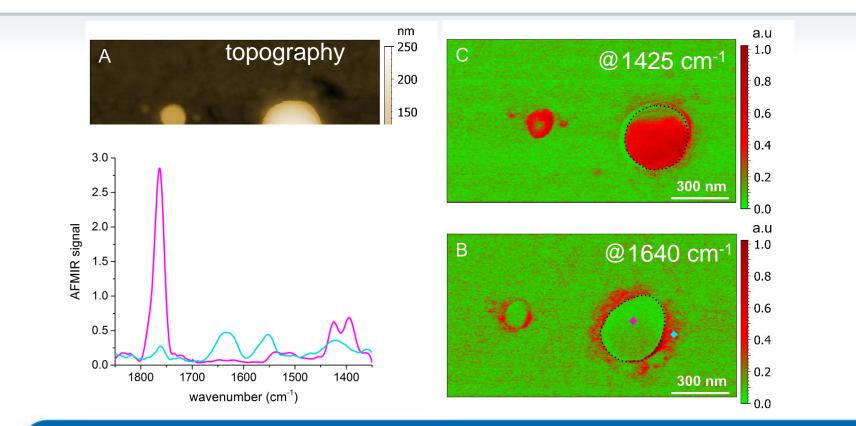
PLA/PVA nanoparticle

Mapping at 1425 cm⁻¹ center on absorption band of PVA





PLGA/PVA nanoparticles with antibiotic

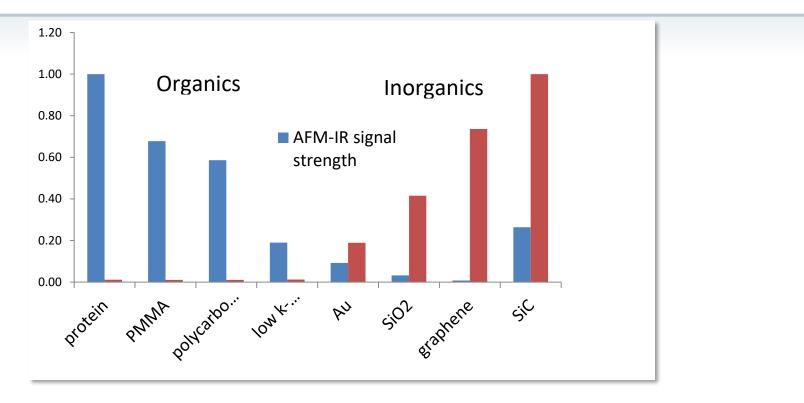




- Better spatial resolution/softer samples via tapping AFM
- Improved chemical imaging via heterodyne detection
 - Insensitive to non-local background forces
- Material selectivity via resonance tuning



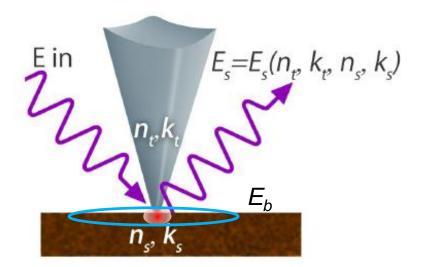
Sensitivity of AFM-IR and s-SNOM



s-SNOM: complex optical property



Metal coated tip acts like an antenna to enhance and localize the light.

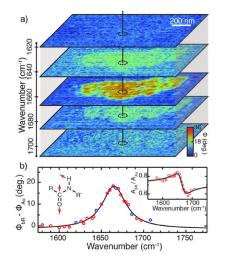


Spatial resolution: tip radius 10~20 nm

Previous: Spatio-spectral Imaging & Broadband Spectroscopy

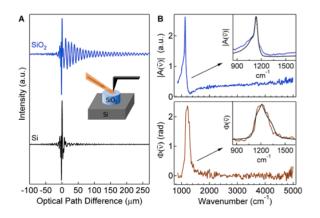


Spatio-spectral Imaging



J. Am. Chem. Soc., 2013, 135, 18292 Disadvantages: slow, limited spectral resolution

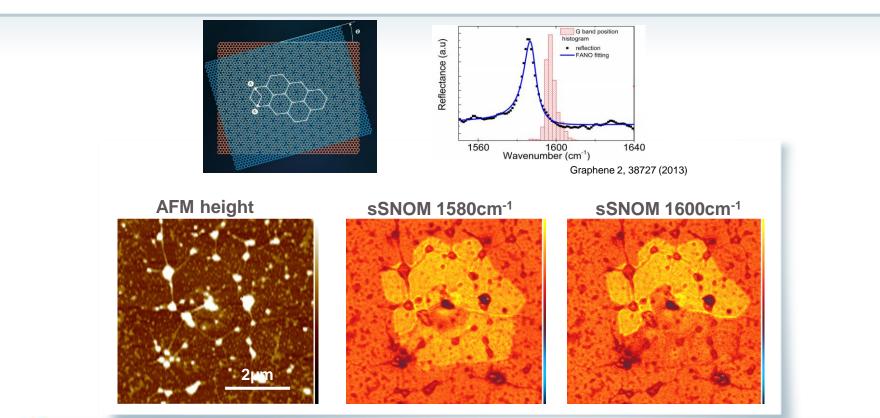
Broadband Spectroscopy



Proc. Natl. Acad. Sci. 111, 7191 (2014) Disadvantages: can't do narrowband imaging (e.g. for compositional mapping)

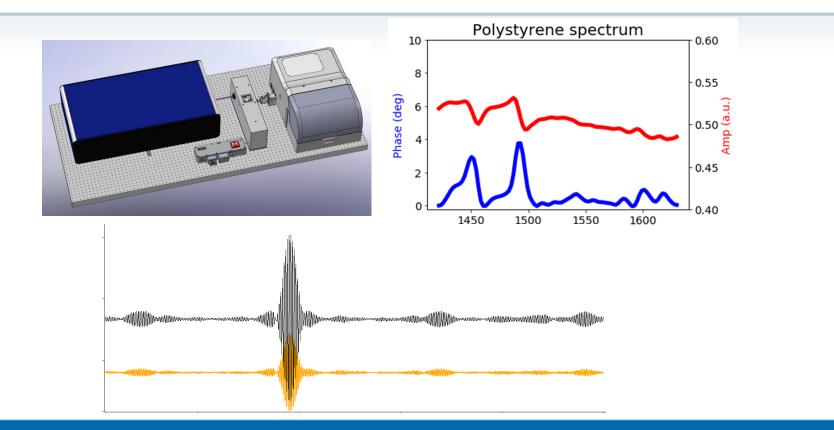


Application: Fano-resonance Bilayer Graphene



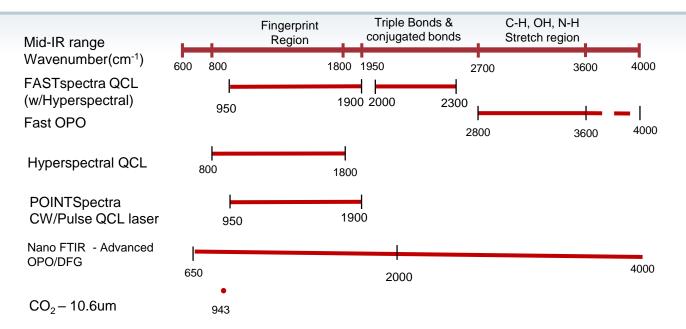
s-SNOM with a broadband laser source





nanoIR Laser Options





- AFM-IR lasers (Pulsed tunable OPO & QCL) can provide both spectroscopy & wavelength specific imaging
- Only CW/P QCL (tunable) lasers provide spectroscopy & wavelength specific imaging for s-SNOM
- nanoFTIR lasers only provide spectroscopy & imaging capabilities (AFM-IR&s-SNOM)

Additional Applications – from 2017-2018 publications



- Life Science
 - Recent paper in Cell Simone Ruggeri, Tuomas Knowles (Cambridge)
 - AFM-IR in Fluid Andrea Centrone (NIST)
 - Malaria Infected Red Blood Cells Bayden Wood (Monash)
 - *In vivo* AFM-IR of Bacteria Bayden Wood (Monash)
- Materials Science
 - Deuterium-labeled polyolefin copolymer blend Dow
 - Core/Shell effect in electrospun PHB copolymer fibers Delaware
 - Functionalized graphene Manchester
 - h-BN Photothermal AFM-IR of 2D Materials Harvard
 - Geoscience Schlumberger & USGS

Additional Applications (continued)



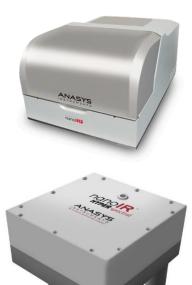
- Atmospheric Aerosols Mark Banaszak Holl (Michigan/Monash)
- Polarized AFM-IR Karsten Hinrichs (ISAS)

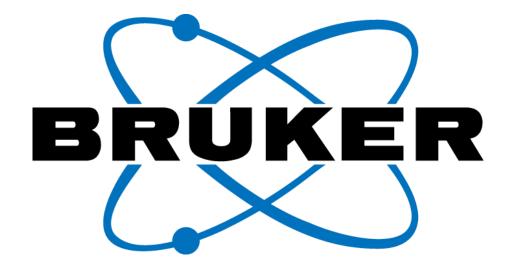
Summary



Recent Technological Advancements in nanoscale IR Technology offers

- Unmatched sensitivity for nanoIR spectroscopy & chemical imaging
- <10nm resolution chemical imaging
- Point spectroscopy in 1-2 secs
- HYPERspectral imaging/Spectroscopy for robust statistical analysis
- Easy to use, high performance AFM imaging with improved noise and sensitivity





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